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FIG.1

FIG.2

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FIG.3

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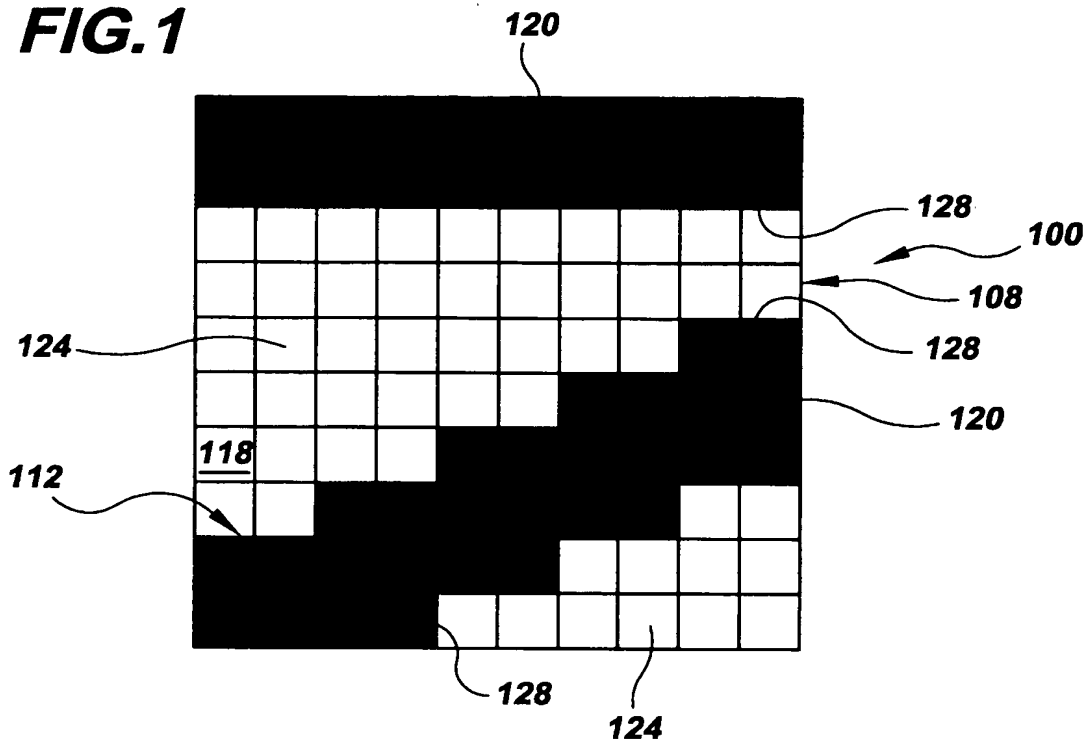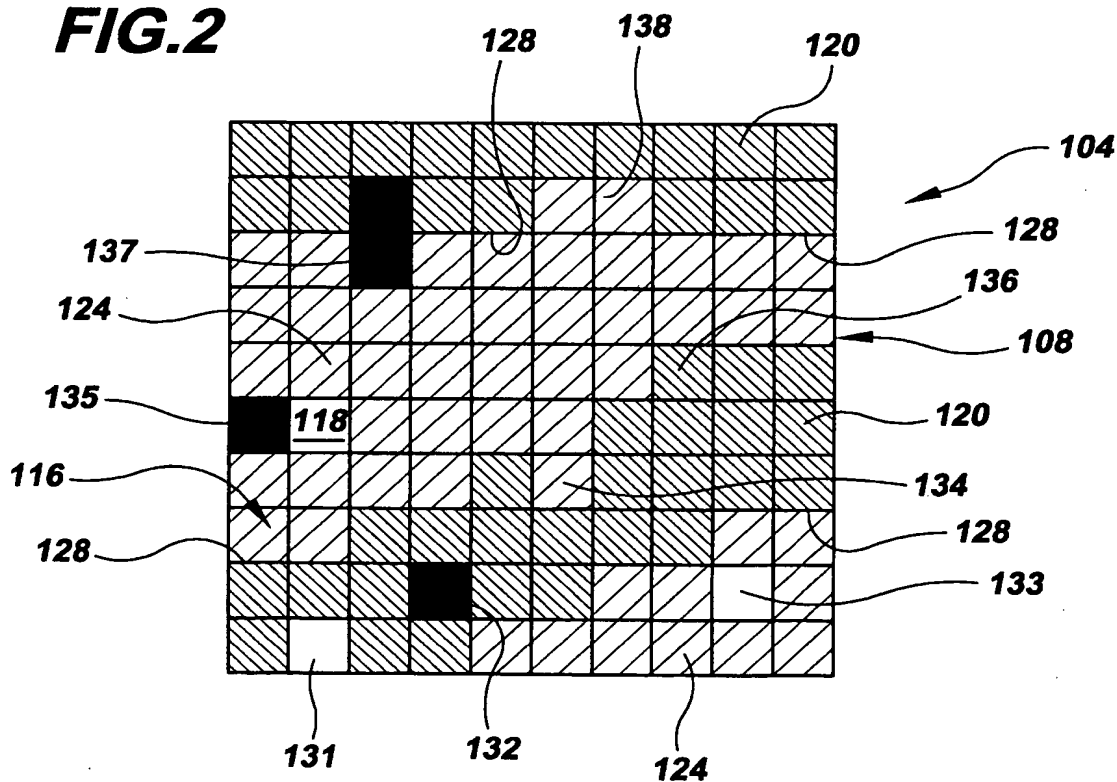Messina et al.
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FIG.4A

FIG.4B

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FIG.5A

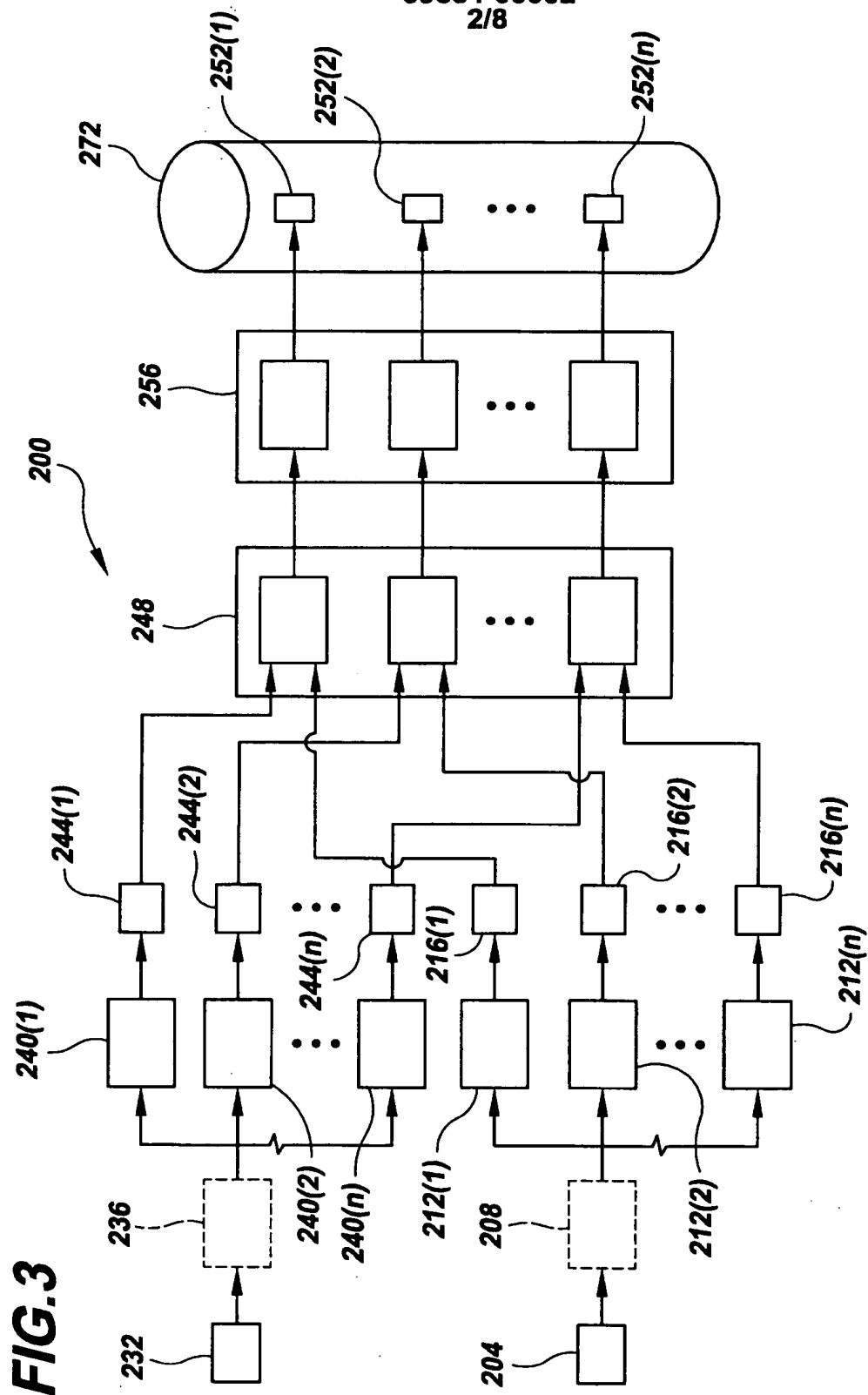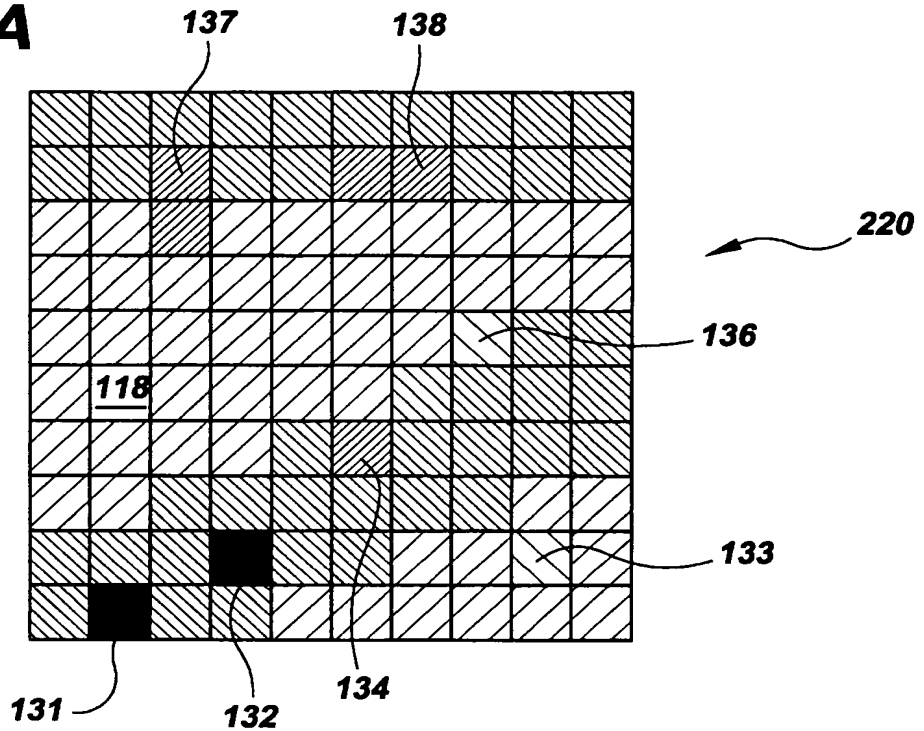137   138

224

136

135

133

134

132

FIG.5B

137   138

264

136

135

134

133

512

132

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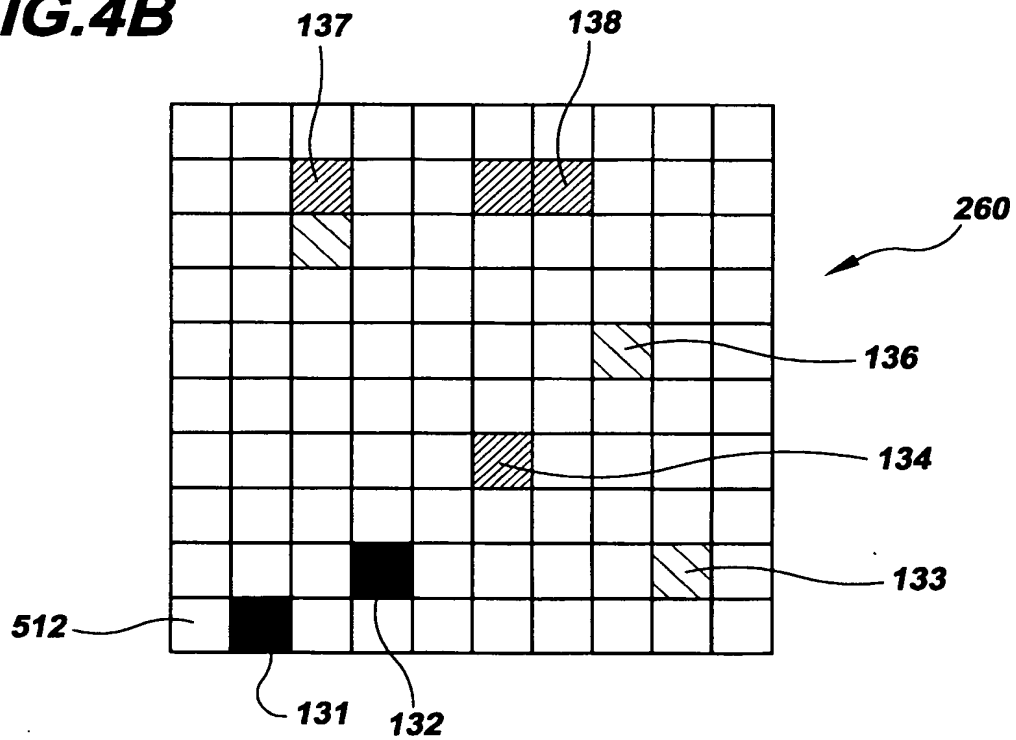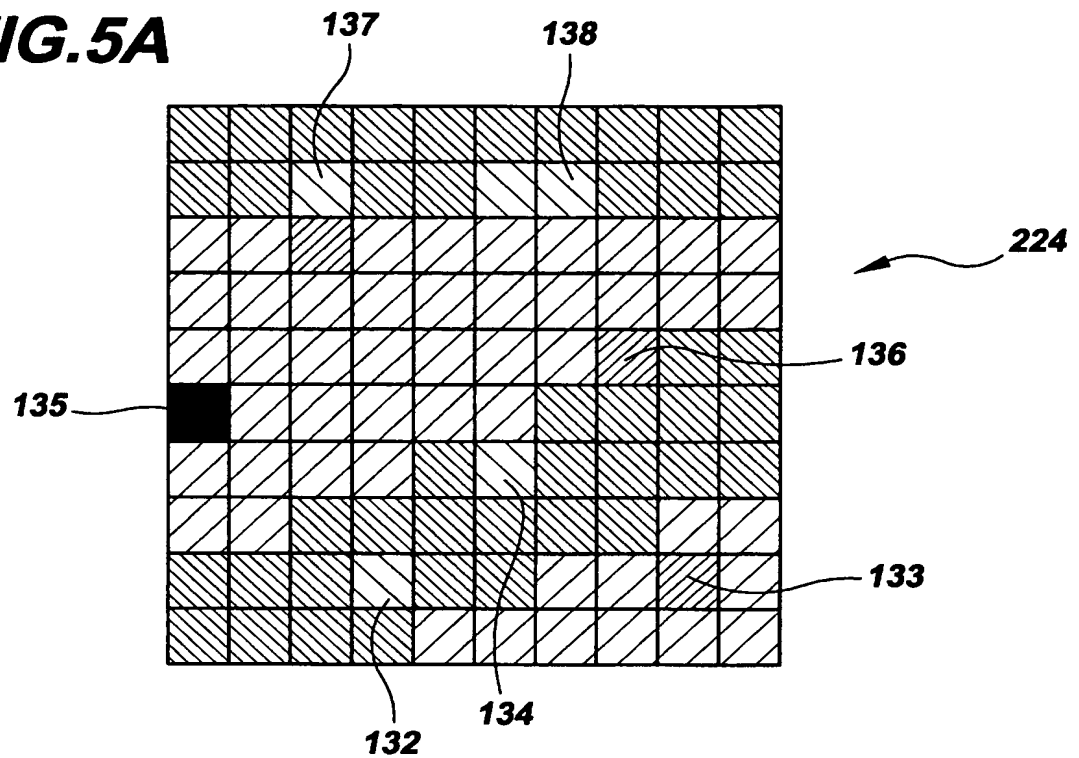Messina et al.
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FIG.6A

FIG.6B

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FIG.7

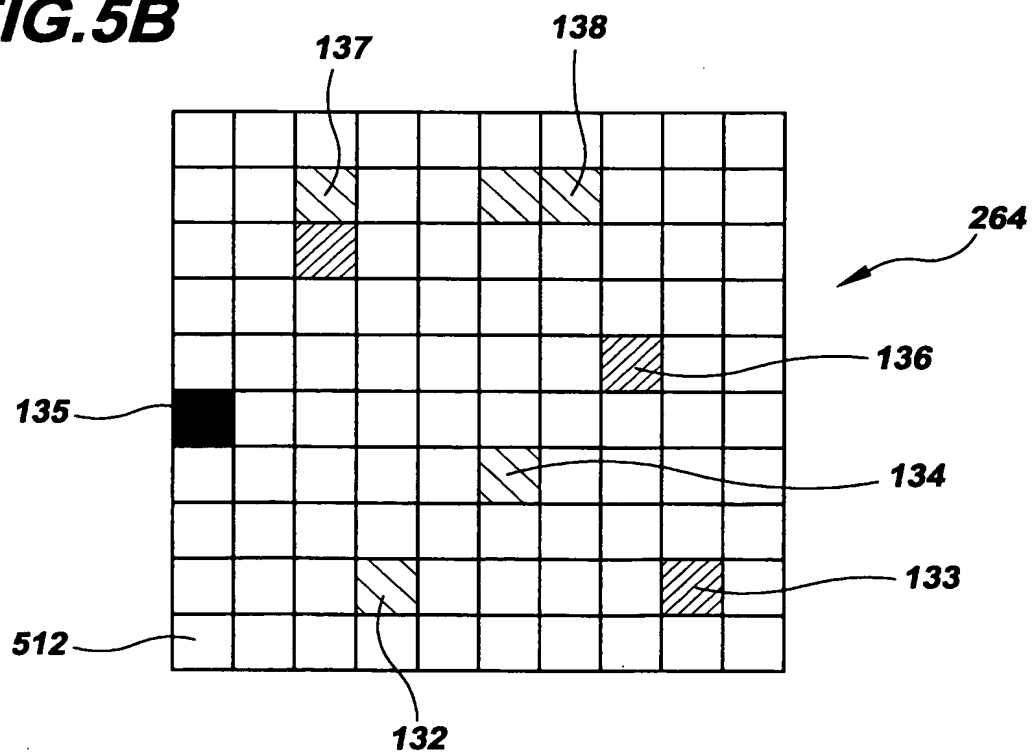## FIG.8

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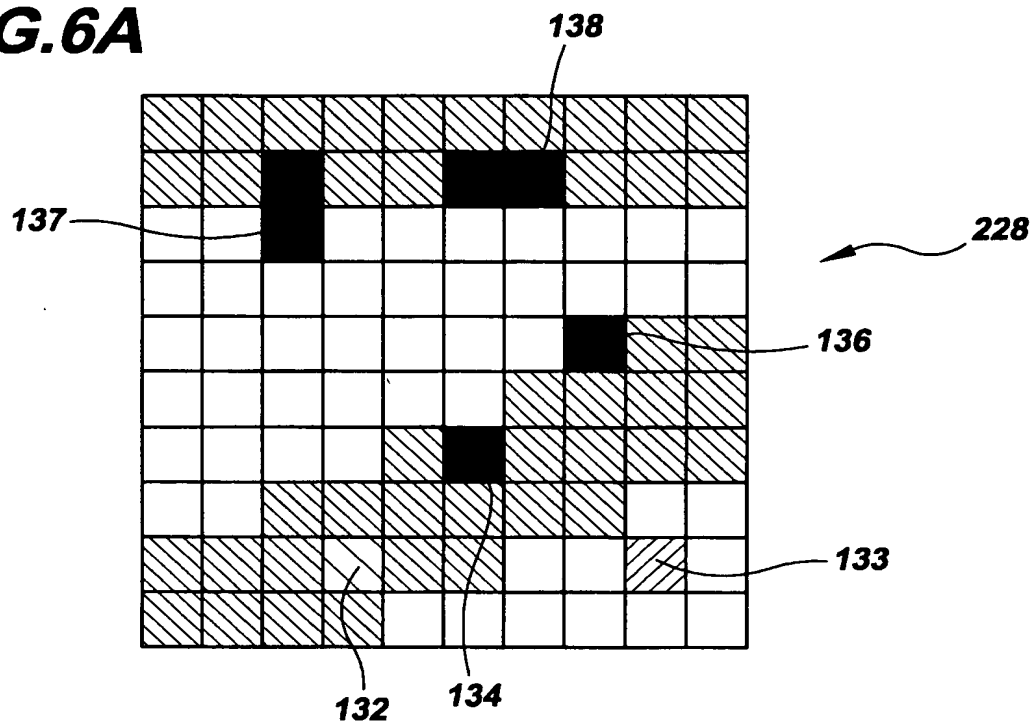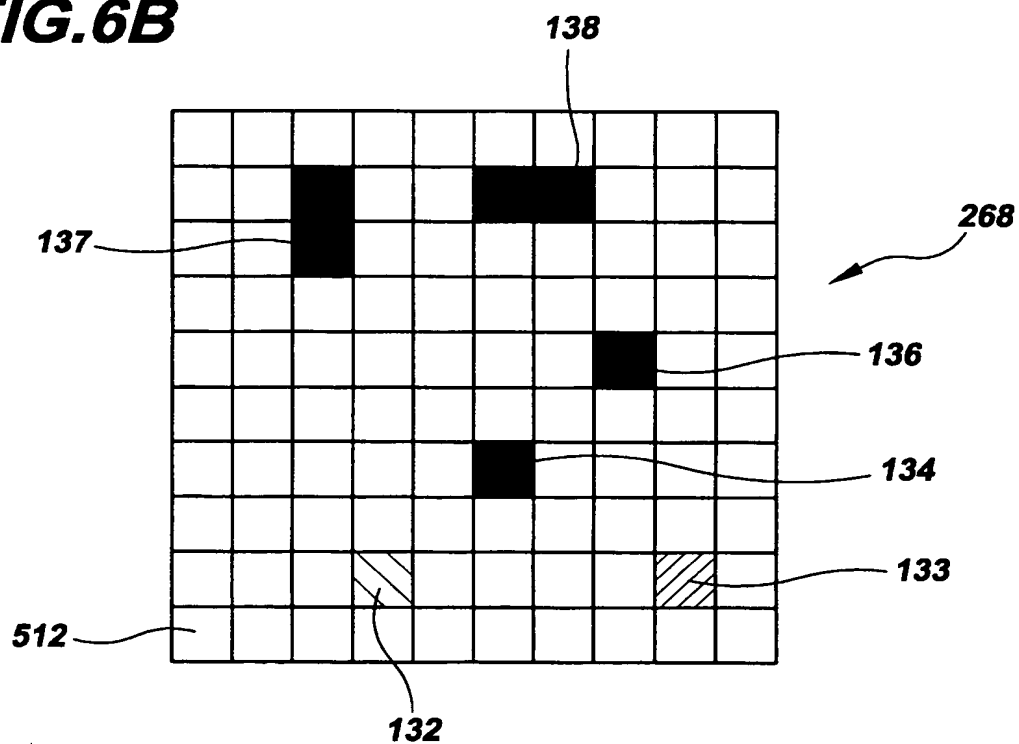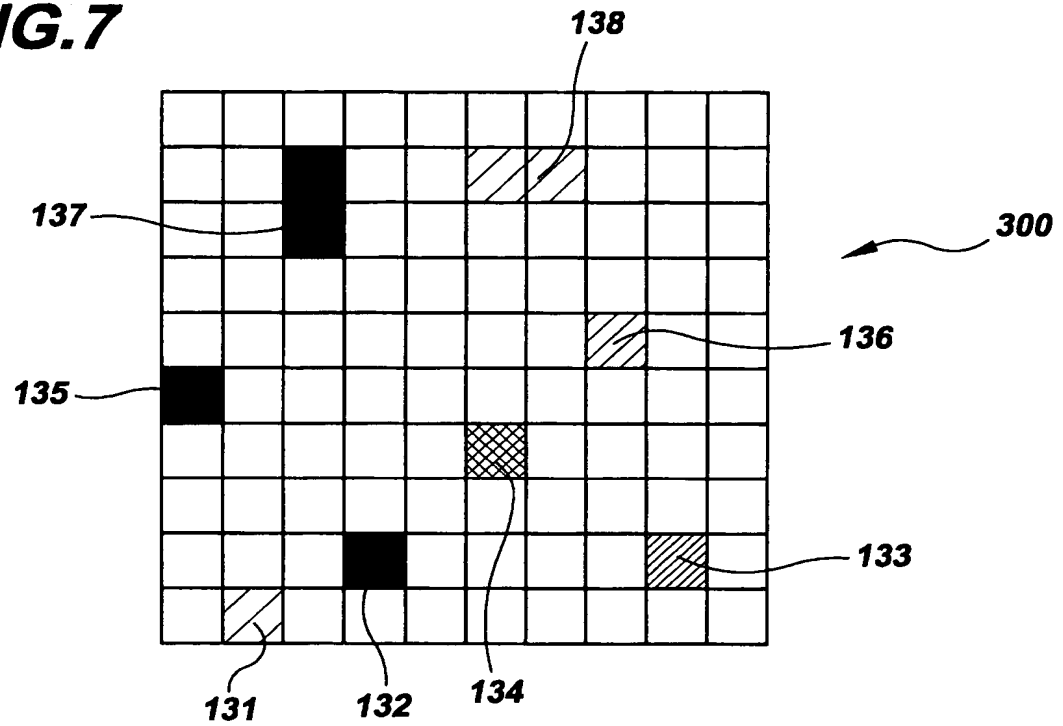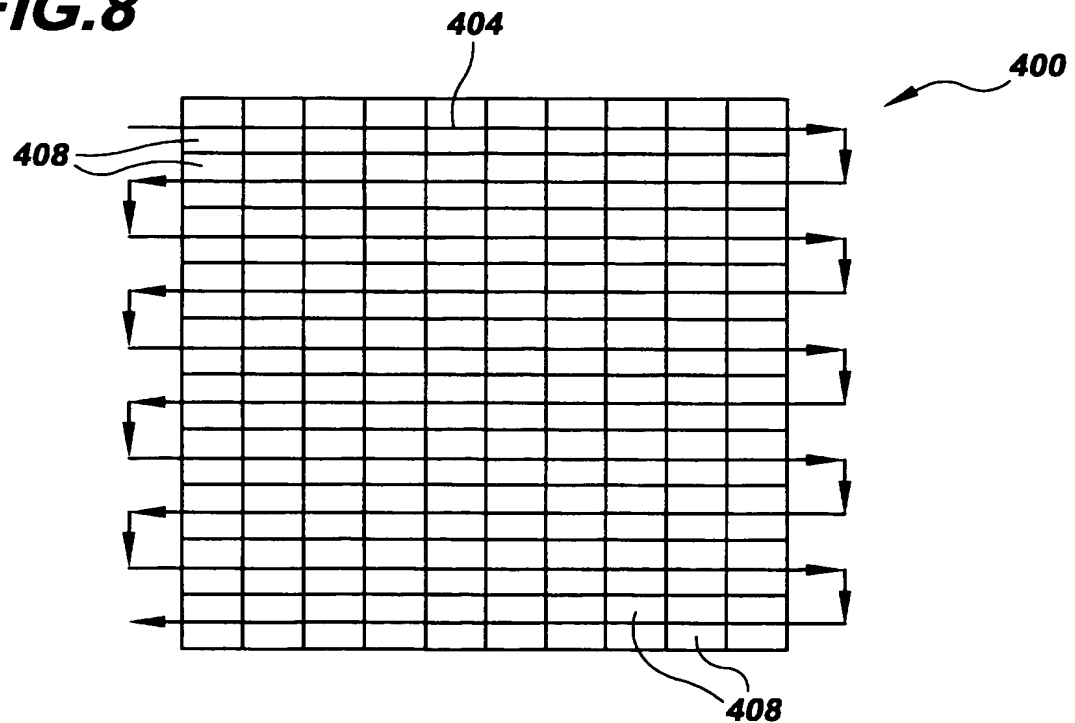Messina et al.
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FIG.9

500

504 — START

508 — SORT ALL DEFECT STRUCTURE BY LOCATION

LAST LOCATION? — YES → END

NO

516 — MORE THAN 1 STRUCTURE FOR LOCATION?

YES

NO

520 — GET NEXT LOCATION SET

524 — LOCATION SET INCLUSIVE? — YES

NO

528 — GET NEXT LOCATION SET

INSIDE STRUCTURE OF INTEREST

532 — LOCATION SET EXCLUSIVELY INSIDE SOI?

NO

YES

536 — PROCESS FOR 1st PRIMARY VARIANT

540 — REPORT DEFECT

544 — GET NEXT LOCATION SET

OUTSIDE STRUCTURE OF INTEREST

LOCATION SET EXCLUSIVELY OUTSIDE SOI? — 548 — NO

YES

552 — PROCESS FOR 2nd PRIMARY VARIANT

556 — REPORT DEFECT

560 — GET NEXT LOCATION SET

ON EDGE OF STRUCTURE OF INTEREST

564 — PROCESS FOR 3rd PRIMARY VARIANT
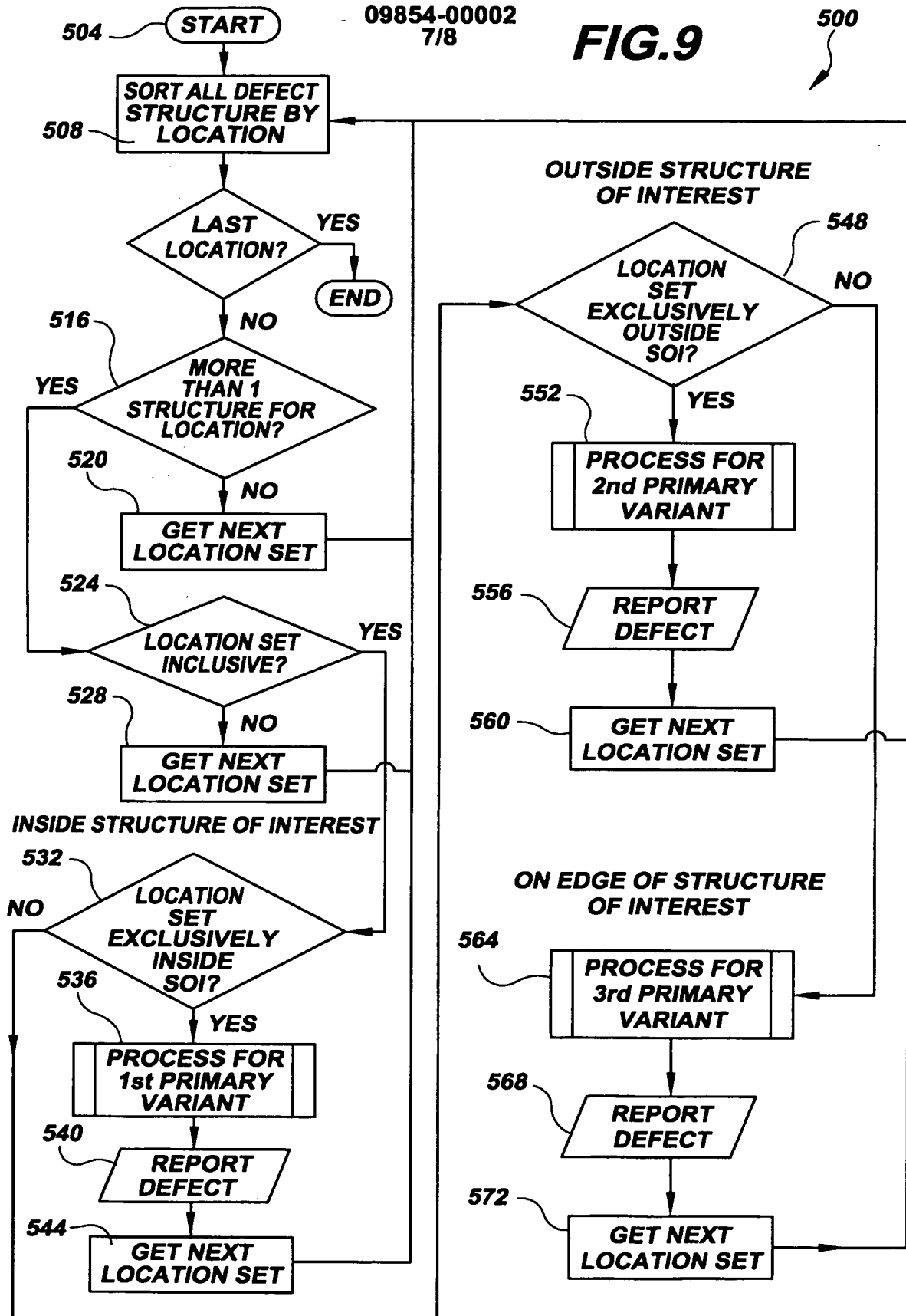
568 — REPORT DEFECT

572 — GET NEXT LOCATION SET

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FIG.10